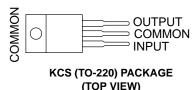
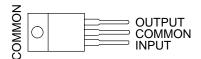
μΑ7800 SERIES POSITIVE-VOLTAGE REGULATORS

SLVS056J - MAY 1976 - REVISED MAY 2003

- 3-Terminal Regulators
- Output Current up to 1.5 A
- Internal Thermal-Overload Protection

KC (TO-220) PACKAGE (TOP VIEW)

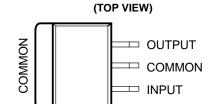




High Power-Dissipation Capability

KTE PACKAGE

- Internal Short-Circuit Current Limiting
- Output Transistor Safe-Area Compensation



description/ordering information

This series of fixed-voltage integrated-circuit voltage regulators is designed for a wide range of applications. These applications include on-card regulation for elimination of noise and distribution problems associated with single-point regulation. Each of these regulators can deliver up to 1.5 A of output current. The internal current-limiting and thermal-shutdown features of these regulators essentially make them immune to overload. In addition to use as fixed-voltage regulators, these devices can be used with external components to obtain adjustable output voltages and currents, and also can be used as the power-pass element in precision regulators.

ORDERING INFORMATION

ТЈ	V _{O(NOM)} (V)	PACKAGET		M) PACKAGET		U I PACKAGET I		ORDERABLE PART NUMBER	TOP-SIDE MARKING
		POWER-FLEX (KTE)	Reel of 2000	μΑ7805CKTER	μA7805C				
	5	TO-220 (KC)	Tube of 50	μΑ7805CKC	A790EC				
		TO-220, short shoulder (KCS)	Tube of 20	μΑ7805CKCS	μA7805C				
		POWER-FLEX (KTE)	Reel of 2000	μΑ7808CKTER	μA7808C				
	8	TO-220 (KC)	Tube of 50	μΑ7808CKC	A7000C				
		TO-220, short shoulder (KCS)	Tube of 20	μΑ7808CKCS	μA7808C				
	10	POWER-FLEX (KTE)	Reel of 2000	μΑ7810CKTER	μA7810C				
0°C to 125°C		TO-220 (KC)	Tube of 50	μΑ7810CKC	μA7810C				
0 C to 125 C		POWER-FLEX (KTE)	Reel of 2000	μΑ7812CKTER	μA7812C				
	12	TO-220 (KC)	Tube of 50	μΑ7812CKC	μΑ7812C				
		TO-220, short shoulder (KCS)	Tube of 20	μΑ7812CKCS	μΑ/612C				
		POWER-FLEX (KTE)	Reel of 2000	μΑ7815CKTER	μA7815C				
	15	TO-220 (KC)	Tube of 50	μΑ7815CKC	A7945C				
		TO-220, short shoulder (KCS)	Tube of 20	μΑ7815CKCS	μA7815C				
	24	POWER-FLEX (KTE)	Reel of 2000	μΑ7824CKTER	μA7824C				
	24	TO-220 (KC)	Tube of 50	μΑ7824CKC	μA7824C				

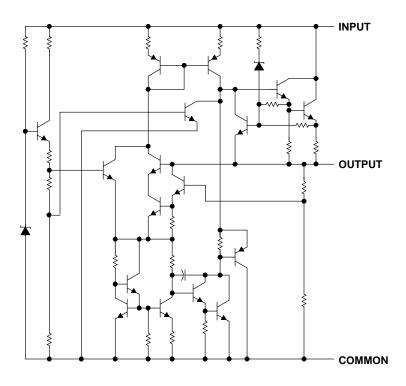
[†] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



schematic



absolute maximum ratings over virtual junction temperature range (unless otherwise noted)†

Input voltage, V _I : μA7824C	40 V
All others	35 V
Operating virtual junction temperature, T _{.j.}	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C
Storage temperature range, T _{stq}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

package thermal data (see Note 1)

PACKAGE	BOARD	θЈС	θ JA
POWER-FLEX (KTE)	High K, JESD 51-5	3°C/W	23°C/W
TO-220 (KC/KCS)	High K, JESD 51-5	3°C/W	19°C/W

NOTE 1: Maximum power dissipation is a function of $T_J(max)$, θ_{JA} , and T_A . The maximum allowable power dissipation at any allowable ambient temperature is $P_D = (T_J(max) - T_A)/\theta_{JA}$. Operating at the absolute maximum T_J of 150°C can affect reliability.



recommended operating conditions

			MIN	MAX	UNIT
		μΑ7805C	7	25	
		μΑ7808C	10.5	25	
V _I Input voltage	μΑ7810C	12.5	28	V	
"	input voitage	μΑ7812C	14.5	30	V
		μΑ7815C	17.5	30	
		μΑ7824C	27	38	
IO Output current			1.5	Α	
TJ	Operating virtual junction temperature	μΑ7800C series	0	125	°C

electrical characteristics at specified virtual junction temperature, $V_{\rm I}$ = 10 V, $I_{\rm O}$ = 500 mA (unless otherwise noted)

PARAMETER	TEST CONDITIONS		_ +	μ Α7805C			UNIT
PARAMETER	IESI COND	ITIONS	T _J †	MIN	TYP	MAX	UNII
Output voltage	$I_O = 5 \text{ mA to 1 A},$	V _I = 7 V to 20 V,	25°C	4.8	5	5.2	V
Output voltage	P _D ≤ 15 W		0°C to 125°C	4.75		FYP MAX 5 5.2 5.25 3 100 1 50 78 15 100 5 50 17 1.1 40 2 4.2 8 1.3	V
Input voltage regulation	V _I = 7 V to 25 V		25°C		3	100	mV
input voltage regulation	V _I = 8 V to 12 V				1	50	
Ripple rejection	$V_{I} = 8 \text{ V to } 18 \text{ V}, \qquad \text{f}$	= 120 Hz	0°C to 125°C	62	78		dB
Output voltage regulation	I _O = 5 mA to 1.5 A		25°C		15	100	mV
Output voltage regulation	I _O = 250 mA to 750 mA				5	50	
Output resistance	f = 1 kHz		0°C to 125°C		0.017		Ω
Temperature coefficient of output voltage	$I_O = 5 \text{ mA}$		0°C to 125°C		-1.1		mV/°C
Output noise voltage	f = 10 Hz to 100 kHz		25°C		40		μV
Dropout voltage	I _O = 1 A		25°C		2		V
Bias current			25°C		4.2	8	mA
Dies surrent change	V _I = 7 V to 25 V		200 / 40500			1.3	A
Bias current change	I _O = 5 mA to 1 A		0°C to 125°C			0.5	mA
Short-circuit output current			25°C		750		mA
Peak output current			25°C		2.2		Α

[†] Pulse-testing techniques maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.1-μF capacitor across the output.



electrical characteristics at specified virtual junction temperature, V_I = 14 V, I_O = 500 mA (unless otherwise noted)

PARAMETER	TEST CONDITIONS	- +	μ Α7808C			UNIT	
PARAMETER	TEST CONDITIONS	TJ [†]	MIN	TYP	MAX	UNIT	
Output voltage	$I_O = 5 \text{ mA to 1 A}, \qquad V_I = 10.5 \text{ V to 23 V},$	25°C	7.7	8	8.3	V	
Output voltage	P _D ≤ 15 W	0°C to 125°C	7.6		8.4	V	
Input voltage regulation	V _I = 10.5 V to 25 V	25°C		6	160	mV	
Input voltage regulation	V _I = 11 V to 17 V	25 C		2	80	IIIV	
Ripple rejection	V _I = 11.5 V to 21.5 V, f = 120 Hz	0°C to 125°C	55	72		dB	
Output valtage regulation	I _O = 5 mA to 1.5 A			12	160	\/	
Output voltage regulation	I _O = 250 mA to 750 mA	25°C		4	80	m∨	
Output resistance	f = 1 kHz	0°C to 125°C		0.016		Ω	
Temperature coefficient of output voltage	$I_O = 5 \text{ mA}$	0°C to 125°C		-0.8		mV/°C	
Output noise voltage	f = 10 Hz to 100 kHz	25°C		52		μV	
Dropout voltage	I _O = 1 A	25°C		2		V	
Bias current		25°C		4.3	8	mA	
Pigg gurrent change	V _I = 10.5 V to 25 V	0°C to 125°C			1	A	
Bias current change	I _O = 5 mA to 1 A	0 0 10 125 0			0.5	mA	
Short-circuit output current		25°C		450		mA	
Peak output current		25°C		2.2		Α	

[†] Pulse-testing techniques maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.1-μF capacitor across the output.

electrical characteristics at specified virtual junction temperature, V_I = 17 V, I_O = 500 mA (unless otherwise noted)

PARAMETER	TEST CONDITIONS		_ +	μ	UNIT		
PARAMETER	TEST CONL	DITIONS	TJ [†]	MIN	TYP	MAX	UNII
Output voltage	$I_0 = 5 \text{ mA to 1 A},$	V _I = 12.5 V to 25 V,	25°C	9.6	10	10.4	V
Output voltage	P _D ≤ 15 W		0°C to 125°C	9.5	10	10.5	V
Input voltage regulation	V _I = 12.5 V to 28 V		25°C		7	200	mV
Input voltage regulation	V _I = 14 V to 20 V		25°C		2	100	IIIV
Ripple rejection	V _I = 13 V to 23 V,	f = 120 Hz	0°C to 125°C	55	71		dB
Output valtage regulation	I _O = 5 mA to 1.5 A I _O = 250 mA to 750 mA		25°C		12	200	m∨
Output voltage regulation			25 C		4	100	
Output resistance	f = 1 kHz		0°C to 125°C		0.018		Ω
Temperature coefficient of output voltage	$I_O = 5 \text{ mA}$		0°C to 125°C		-1		mV/°C
Output noise voltage	f = 10 Hz to 100 kHz		25°C		70		μV
Dropout voltage	I _O = 1 A		25°C		2		V
Bias current			25°C		4.3	8	mA
Dies surrent shangs	V _I = 12.5 V to 28 V		0°C to 125°C			1	mA
Bias current change	I _O = 5 mA to 1 A		0-0 10 125-0			0.5	IIIA
Short-circuit output current			25°C		400		mA
Peak output current			25°C		2.2		Α

[†] Pulse-testing techniques maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-µF capacitor across the input and a 0.1-µF capacitor across the output.



electrical characteristics at specified virtual junction temperature, V_I = 19 V, I_O = 500 mA (unless otherwise noted)

DADAMETED	TEST COMPITIONS	_ +	μ Α7812C			LINIT
PARAMETER	TEST CONDITIONS	TJ [†]	MIN	TYP	MAX	UNIT
Output voltage	$I_O = 5 \text{ mA to 1 A}, \qquad V_I = 14.5 \text{ V to 27 V},$	25°C	11.5	12	12.5	V
Output voltage	$P_D \le 15 \text{ W}$	0°C to 125°C	11.4		12.6	V
Input voltage regulation	V _I = 14.5 V to 30 V	25°C		10	240	
Input voltage regulation	V _I = 16 V to 22 V	25.0		3	120	mV
Ripple rejection	V _I = 15 V to 25 V, f = 120 Hz	0°C to 125°C	55	71		dB
Output valtage regulation	I _O = 5 mA to 1.5 A	25°C		12	240	-l m∨ l
Output voltage regulation	I _O = 250 mA to 750 mA			4	120	
Output resistance	f = 1 kHz	0°C to 125°C		0.018		Ω
Temperature coefficient of output voltage	$I_O = 5 \text{ mA}$	0°C to 125°C		-1		mV/°C
Output noise voltage	f = 10 Hz to 100 kHz	25°C		75		μV
Dropout voltage	I _O = 1 A	25°C		2		V
Bias current		25°C		4.3	8	mA
Dies surrent change	V _I = 14.5 V to 30 V		1		1	mA
Bias current change	I _O = 5 mA to 1 A	0°C to 125°C		0.5		
Short-circuit output current		25°C		350		mA
Peak output current		25°C		2.2		Α

[†] Pulse-testing techniques maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-µF capacitor across the input and a 0.1-µF capacitor across the output.

electrical characteristics at specified virtual junction temperature, V_I = 23 V, I_O = 500 mA (unless otherwise noted)

PARAMETER	TEST CONDITIONS	_ +	μ Α7815C			UNIT	
PARAMETER	TEST CONDITIONS	TJ [†]	MIN	TYP	MAX	UNIT	
Output voltage	$I_O = 5 \text{ mA to 1 A}, \qquad V_I = 17.5 \text{ V to 30 V},$	25°C	14.4	15	15.6	V	
Output voltage	$P_D \le 15 \text{ W}$	0°C to 125°C	14.25		15.75	V	
Input voltage regulation	V _I = 17.5 V to 30 V	25°C		11	300	mV	
input voltage regulation	V _I = 20 V to 26 V	25 C		3	150	IIIV	
Ripple rejection	V _I = 18.5 V to 28.5 V, f = 120 Hz	0°C to 125°C	54	70		dB	
Output voltage regulation	$I_O = 5$ mA to 1.5 A	25°C		12	300	mV	
Output voltage regulation	I _O = 250 mA to 750 mA	25 C		4	150		
Output resistance	f = 1 kHz	0°C to 125°C		0.019		Ω	
Temperature coefficient of output voltage	$I_O = 5 \text{ mA}$	0°C to 125°C		-1		mV/°C	
Output noise voltage	f = 10 Hz to 100 kHz	25°C		90		μV	
Dropout voltage	I _O = 1 A	25°C		2		V	
Bias current		25°C		4.4	8	mA	
Pigg current change	V _I = 17.5 V to 30 V	0°C to 125°C			1	m ^	
Bias current change	I _O = 5 mA to 1 A	0.0 10 125.0			0.5	mA	
Short-circuit output current		25°C		230		mA	
Peak output current		25°C		2.1		Α	

[†] Pulse-testing techniques maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.1-μF capacitor across the output.



electrical characteristics at specified virtual junction temperature, $V_I = 33 \text{ V}$, $I_O = 500 \text{ mA}$ (unless otherwise noted)

DADAMETED	TEST 60	TEST CONDITIONS		μ Α7824C			UNIT
PARAMETER	TEST CONDITIONS		TJ [†]	MIN	TYP	MAX	UNIT
Output voltage	$I_0 = 5 \text{ mA to 1 A},$	$V_{I} = 27 \text{ V to } 38 \text{ V},$	25°C	23	24	25	V
Output voltage	$P_D \le 15 \text{ W}$	0°C to 125°C	22.8		25.2	V	
Input voltage regulation	V _I = 27 V to 38 V		25°C		18	480	mV
Input voltage regulation	V _I = 30 V to 36 V		25 C		6	240	IIIV
Ripple rejection	V _I = 28 V to 38 V,	f = 120 Hz	0°C to 125°C	50	66		dB
Output valtage regulation	I _O = 5 mA to 1.5 A I _O = 250 mA to 750 mA		- 25°C		12	480	mV
Output voltage regulation					4	240	
Output resistance	f = 1 kHz		0°C to 125°C		0.028		Ω
Temperature coefficient of output voltage	$I_O = 5 \text{ mA}$		0°C to 125°C		-1.5		mV/°C
Output noise voltage	f = 10 Hz to 100 kHz		25°C		170		μV
Dropout voltage	I _O = 1 A		25°C		2		V
Bias current			25°C		4.6	8	mA
Pigg gurrent change	V _I = 27 V to 38 V I _O = 5 mA to 1 A		0°C to 125°C	1		mΛ	
Bias current change			0 0 10 125 0			0.5	mA
Short-circuit output current			25°C		150		mA
Peak output current		-	25°C		2.1		Α

[†] Pulse-testing techniques maintain the junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.33-μF capacitor across the input and a 0.1-μF capacitor across the output.



APPLICATION INFORMATION

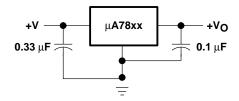


Figure 1. Fixed-Output Regulator

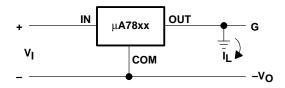
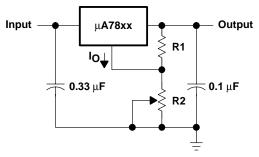


Figure 2. Positive Regulator in Negative Configuration (V_I Must Float)



NOTE A: The following formula is used when V_{XX} is the nominal output voltage (output to common) of the fixed regulator:

$$V_{O} = V_{xx} + \left(\frac{V_{xx}}{R1} + I_{Q}\right)R2$$

Figure 3. Adjustable-Output Regulator

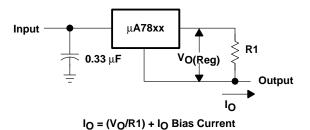


Figure 4. Current Regulator

APPLICATION INFORMATION

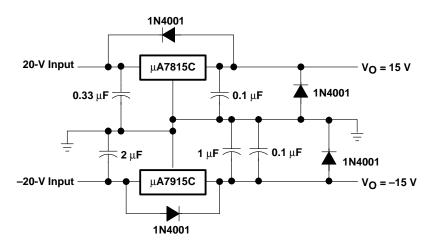


Figure 5. Regulated Dual Supply

operation with a load common to a voltage of opposite polarity

In many cases, a regulator powers a load that is not connected to ground but, instead, is connected to a voltage source of opposite polarity (e.g., operational amplifiers, level-shifting circuits, etc.). In these cases, a clamp diode should be connected to the regulator output as shown in Figure 6. This protects the regulator from output polarity reversals during startup and short-circuit operation.

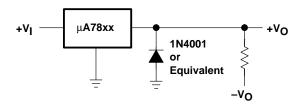


Figure 6. Output Polarity-Reversal-Protection Circuit

reverse-bias protection

Occasionally, the input voltage to the regulator can collapse faster than the output voltage. This can occur, for example, when the input supply is crowbarred during an output overvoltage condition. If the output voltage is greater than approximately 7 V, the emitter-base junction of the series-pass element (internal or external) could break down and be damaged. To prevent this, a diode shunt can be used as shown in Figure 7.

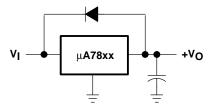
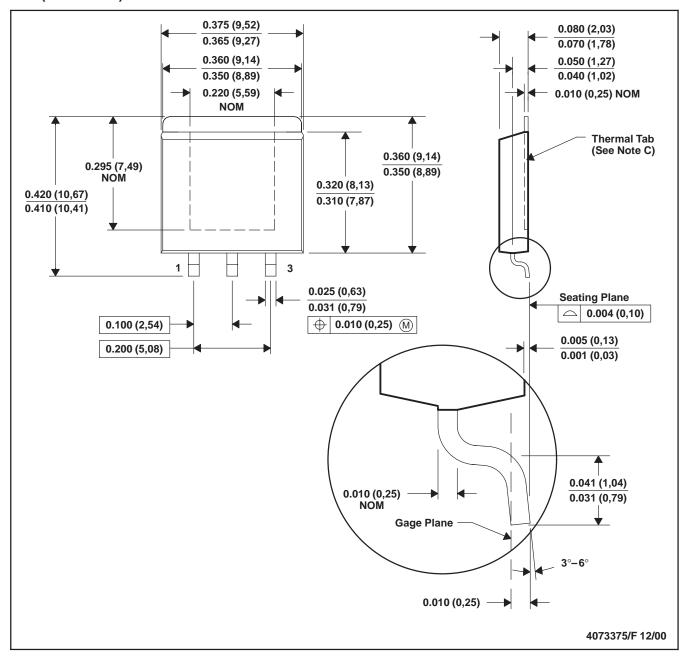


Figure 7. Reverse-Bias-Protection Circuit



KTE (R-PSFM-G3)

PowerFLEX™ PLASTIC FLANGE-MOUNT

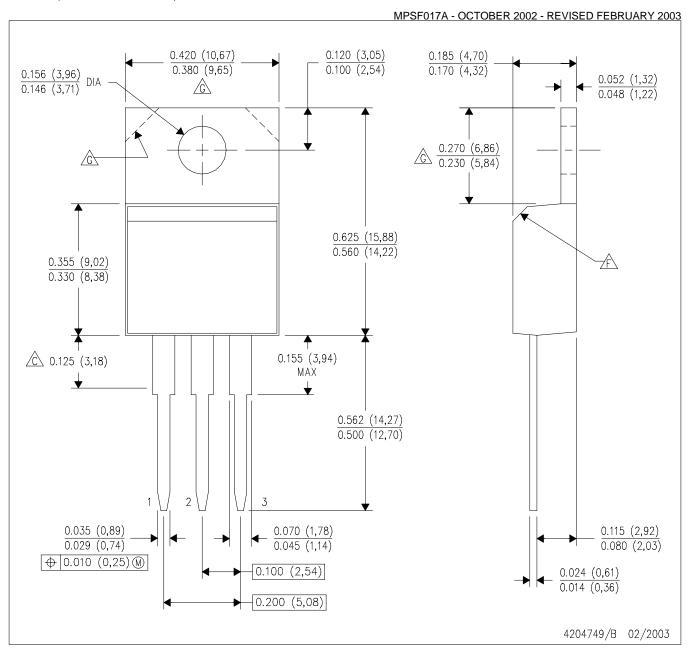


NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. The center lead is in electrical contact with the thermal tab.
- D. Dimensions do not include mold protrusions, not to exceed 0.006 (0,15).
- E. Falls within JEDEC MO-169

PowerFLEX is a trademark of Texas Instruments.





NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.

Lead dimensions are not controlled within this area.

- D. All lead dimensions apply before solder dip.
- E. The center lead is in electrical contact with the mounting tab.

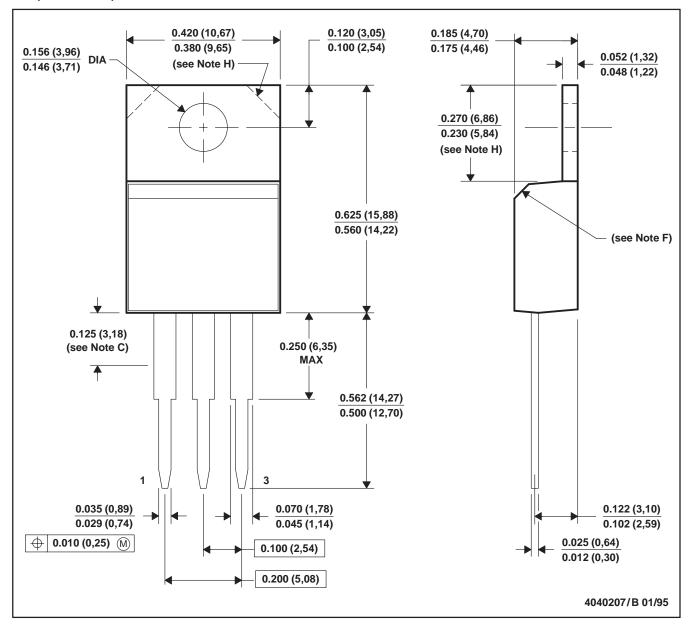
The chamfer is optional.

Tab contour optional within these dimensions.

H. Falls within JEDEC TO-220 variation AB.

KC (R-PSFM-T3)

PLASTIC FLANGE-MOUNT PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Lead dimensions are not controlled within this area.
- D. All lead dimensions apply before solder dip.
- E. The center lead is in electrical contact with the mounting tab.
- F. The chamfer is optional.
- G. Falls within JEDEC TO-220AB
- H. Tab contour optional within these dimensions



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